

IEC QUALITY ASSESSMENT SYSTEM (IECQ) covering Electronic Components,

Assemblies, Related Materials and Processes For rules and details of the IECQ visit www.iecq.org

## Schedule of Scope to Certificate of Approval

Independent Testing Laboratory

IECQ Certificate No.: IECQ-L ULTW 15.0001

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1. Reliability Test (International standards, including JEDEC, IPC, EIA, AEC, MIL, ...etc.):

Test Items	Standard/Method
High Temperature Storage Test	JEDEC / JESD22-A103
Low Temperature Storage Test	JEDEC / JESD22-A119
Temperature Humidity Storage Test	JEDEC / JESD22-A101
Temperature Cycling Test	JEDEC / JESD22-A104
Highly-Accelerated Temperature and Humidity Stress Test (HAST)	JEDEC / JESD22-A110
Light Exposure Test	Base on Customer's requirements
Heat Resistance Test	Base on Customer's requirements

2. Failure Analysis of integrated circuits, including, Optical Microscope (OM), Scanning Electron Microscope (SEM) / Energy Dispersive Spectrometer (EDS) and transmittance measurement.

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DQS UL Group - UL DQS Taiwan Inc., Feng Yuan Dist., Taichung City, Taiwan

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